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				Application Number	10/735,110
INFO	PRMATION	I DISC	CLOSURE	Filing Date	12/12/2003
STATEMENT BY APPLICANT				First Named Inventor	Nimmakayala et al.
				Group Art Unit	Unassigned
(use as many sheets as necessary)				Examiner Name	Unassigned
Sheet	3	of	4	Attorney Docket Number	P122/MII-94-69V18

OTHER PRIO	R ART -	NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(spublisher, city and/or country where published.			
LBT	C5	KRUG et at., "Fine Patterning of Thin Sol-Gel Films," Journal of Non-Crystalline Solids, 1992, pp. 447-450, vol. 147 & 148.			
	C6	Krauss et al., "Fabrication of Nanodevices Using Sub-25nm Imprint Lithography," Appl. Phys. Lett 67(21), 3114-3116, 1995			
	C7	CHOI et al., "Method and System of Automatic Fluid Dispensing for Imprint Lithography Processes," U.S. Patent Application Publication 2002/0094496. Published on July 18, 2002.			
	C8	CHOI et al., "Methods for High-Precision Gap and Orientation Sensing Between a Transparent Template and Substrate for Imprint Lithography," U.S. Patent Application Publication 2003/0093122. Published on July 18, 2002. 5 2003			
	C9	VOISIN, "Methods of Manufacturing a Lithography Template," U.S. Patent Application 10/136,188, Filed with USPTO on May 1, 2002.			
	C10	SREENIVASAN et al., "Step and Repeat Imprint Lithography Systems," U.S. Patent Application 10/194,414. Filed with USPTO July 11, 2002.			
	C11	SREENIVASAN et al., "Step and Repeat Imprint Lithography Processes," U.S. Patent Application 10/194,991. Filed with USPTO July 11, 2002.			
	C12	OTTO M. et al., "Step and Repeat UV-Nanoimprint Lithography: Material Issues," Nanoimprint and Nanoprint Technology Conference, San Francisco, December 11-13, 2002.			
	C13	JOHNSON, et al., "Advances in Step and Flash Imprint Lithography, " SPIE Microlithography Conference, February 23-28, 2003.			
V	C14	CHOI et al., "A Chucking System and Method for Modulating Shapes of Subtrates," U.S. Patent Application 10/293,224. Filed with USPTO on November 13, 2002.			
LBT	C15	CHOI et al., "A Method For Modulating Shapes of Substrates," U.S. Patent Application 10/316,963. Filed with USPTO on December 11, 2002.			

Examiner Signature	/Leo B. Tentoni/	Date Considered	01/20/2007

^{*}EXAMINER: Initial If reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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